	Application No.	Applicant(s)
		, ipp.:(c)
Notice of Allowability	09/382,834	BEAMAN ET AL.
	Examiner	Art Unit
	VINH P. NGUYEN	2829
The MAILING DATE of this communication appear All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI	(OR REMAINS) CLOSED in th or other appropriate communic GHTS. This application is sub	is application. If not included cation will be mailed in due course. <b>THIS</b>
1. This communication is responsive to <u>10/29/08</u> .		
2. X The allowed claim(s) is/are 29,31,33-34,36-37,42-43,53-58	3 <u>,88-94,109-118,140-148</u> .	
<ul> <li>3. ☐ Acknowledgment is made of a claim for foreign priority ur</li> <li>a) ☐ All b) ☐ Some* c) ☐ None of the:</li> <li>1. ☐ Certified copies of the priority documents have</li> <li>2. ☐ Certified copies of the priority documents have</li> <li>3. ☐ Copies of the certified copies of the priority documents.</li> </ul>	been received. been received in Application N	No
<ol> <li>Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).</li> </ol>		
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.  4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give	IENT of this application. itted. Note the attached EXAMI	NER'S AMENDMENT or NOTICE OF
5. CORRECTED DRAWINGS ( as "replacement sheets") mus	et be submitted.	
(a) ☐ including changes required by the Notice of Draftspers		PTO-948) attached
1) hereto or 2) to Paper No./Mail Date	•	,
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1	.84(c)) should be written on the c	drawings in the front (not the back) of
each sheet. Replacement sheet(s) should be labeled as such in the 6. DEPOSIT OF and/or INFORMATION about the depo	_	
attached Examiner's comment regarding REQUIREMENT		
Attachment(s)  1. ☐ Notice of References Cited (PTO-892)  2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)  3. ☐ Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date  4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ⊠ Interview Sum Paper No./Ma 7. ⊠ Examiner's An	il Date <u>10/31/08</u> .

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1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

In claim 31, line 1, ---30--- has been changed to ---29---.

In claim 88, line 2, ---59--- has been changed to ---58---.

Claims 49,59-87 and 139 have been canceled.

Claims 30-32,35,38-41,44 and 51 have been canceled.

New added claims 140-148 as follows:

Claim 140 (new) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein the electronic component is a semiconductor wafer.

Claim 141 (new) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein the area of the electronic component is a portion of a surface area of the electronic component.

Claim 142 (new) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein the flexible elements are probe elements.

Claim 143 (new) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein there are electrical connections between the second substrates and the first substrate.

Claim 144 (new) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein the first substrate is a space transformer.

Claim 145 (New) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contact individual semiconductor dies on the semiconductor wafer.

Claim 146 (New) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein the electronic component is a semiconductor wafer; and the flexible contact elements of the second substrate contacts at least one integrated circuit on the semiconductor wafer.

Claim 147 (New) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein the first substrate with the second substrate mounted thereto is mounted to an electrical testing apparatus by a plurality of electrical connections.

Claim 148 (New) A method according to any one of claims 29, 33, 34, 36, 37, 42, 43 or 53 to 59, wherein there is a least one second substrate is mounted to said first substrate.

- 2. Authorization for this examiner's amendment was given in a telephone interview with Mr. Morris on 10/31/08.
- 3. The drawings filed on 08/25/99 and 07/30/08 is acceptable.

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4. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to VINH P. NGUYEN whose telephone number is 571-272-1964.

The examiner can normally be reached on 6:30AM-4:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, HA T. NGUYEN can be reached on 571-272-1678. The fax phone number for the

organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent

Application Information Retrieval (PAIR) system. Status information for published applications

may be obtained from either Private PAIR or Public PAIR. Status information for unpublished

applications is available through Private PAIR only. For more information about the PAIR

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like assistance from a USPTO Customer Service Representative or access to the automated

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/VINH P NGUYEN/ Primary Examiner

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